

Title of Change:		Qualify ON Semiconductor, Cebu Test and Finish Process for NCP81218 (QFN48 6x6) and NCP81203 (QFN52 6x6) as Second Source of ON Semiconductor, Carmona Test and Finish.			
Proposed First Ship date	: 12 September 2019 or earlier upon custome	12 September 2019 or earlier upon customer approval			
Contact Information:	Contact your local ON Semiconductor Sales (Contact your local ON Semiconductor Sales Office or < <u>Raymond.ODell@onsemi.com</u> >			
Samples:	Contact your local ON Semiconductor Sales (Samples should be available after completion of qualification. Contact your local ON Semiconductor Sales Office or < <u>PCN.samples@onsemi.com</u> > Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change.			
Type of Notification:	to implementation of the change. ON Semiconductor will consider this change	This is an Initial Product/Process Change Notification (IPCN) sent to customers. IPCNs are issued 90 days prio to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days o delivery of this notice. To do so, contact < <u>PCN.Support@onsemi.com></u>			
Change Part Identificatio	Philippines from Sept 04th, 2019 once the F	Customer may receive the parts from ON Semiconductor's facility in Carmona, Philippines and Cebu, Philippines from Sept 04 th , 2019 once the PCN expires or earlier depending on customer's approval. Parts tested in ON Carmona & On Cebu and can be identified through product packaging and labelling which follow ON Semiconductor standard.			
Change Category:	Wafer Fab Change Assembly C	Wafer Fab Change Assembly Change V Test Change Other			
Change Sub-Category(s): Manufacturing Site Ad Manufacturing Site Tra Manufacturing Proces	ddition I Material Change I Product specific change	[[[Datasheet/Product Doc change Shipping/Packaging/Marking Other: 		
Sites Affected:	ON Semiconductor Sites : ON Carmona, Philippines ON Cebu, Philippines	External Foundry/Subcon Sites: None			
Description and Purpose	2:				
	Before Change Description		After Change Description		
Location	ON Semiconductor, Carmona, Philippines	After the change, Final Test will be done in ON Carmona, Philippines & ON Cebu, Philippines.			
Test equipment	ON Carmona Only: Teradyne ETS800 tester + Multitest MT2168 handler	ON Carmona & ON Cebu Teradyne ETS800 tester + Multitest MT2168 handler <i>(same equipment sets)</i>			



Qualification Plan:

Complete the qualification requirement per plan. The scope is to perform electrical test on the new test site and confirm comparable results achieved with the existing test site:

Qualification Items/Steps	Quality Characteristic / Response to be Monitored (Input, in-process, Output)	Test /Condition	Sample Size	Accept Criteria / Result
Key Parameter Electrical Distribution Comparison (Carmona & Cebu)	Between Carmona and Cebu: Correlation GRR Repeatability Spike Check Cpk	FT Room Temp 25°C	16, 1 unit per site 16, 1 unit per site 16, 1 unit x 100 loop 1 unit 1 site only Lot qty	<10% on critical items <10% CP >10 No more than AMR >1.67
Reject Bin Analysis	KBU or Escape rate	FT Room Temp 25°C	All KBU or ESC	Bin out correctly
Test (Yield, GDPW, Correlation, etc.)	Test fresh lots on each qual vehicle	FT Room Temp 25°C	3 lots (3000 units)	90% Yield min, and 1% max difference, base from Carmona
Electrical QA	Auto QA process per lot	FT Room Temp 25°C	500 units per lot	0 QA reject

List of Affected Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the **PCN Customized Portal**.

Part Number	Qualification Vehicle	
NCP81203MNTXG	NCP81203MNTXG	
NCP81218MNTXG	NCP81218MNTXG	



Appendix A: Changed Products

Product	Customer Part Number	Qualification Vehicle
NCP81203MNTXG		NCP81203MNTXG
NCP81218MNTXG		NCP81218MNTXG